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EMC IC modelling - Part 1: General modelling framework

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ICS 31.200

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EUROPEAN STANDARD

NORME EUROPÉENNE

EUROPÄISCHE NORM

EN IEC 62433-1

April 2019

ICS 31.200

English Version

EMC IC modelling - Part 1: General modelling framework (IEC 62433-1:2019)

Modèles de circuits intégrés pour la CEM - Partie 1: Cadre de modèle général (IEC 62433-1:2019)

EMV-IC-Modellierung - Teil 1: Allgemeine Modellierungsstruktur (IEC 62433-1:2019)

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European Committee for Electrotechnical Standardization
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Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 47A/1042/CDV, future edition 1 of IEC 62433-1, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62433-1:2019.

The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2020-01-12
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2022-04-12

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The text of the International Standard IEC 62433-1:2019 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

CISPR 17	NOTE	Harmonized as EN 55017

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Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

Publication	Year	Title	EN/HD	Year
IEC 62433	series	EMC IC modelling	EN 62433	series
ISO 8879	-	Information processing - Text and office systems - Standard Generalized Markup Language (SGML)	-	-
ANSI INCITS 4	1986	Information Systems - Coded Character Sets - 7-Bit American National Standard Code for Information Interchange (7-Bit ASCII)	-	-

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EMC IC MODELLING –

Part 1: General modelling framework

FOREWORD

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International Standard IEC 62433-1 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

IEC 62433-1 cancels and replaces IEC TS 62433-1 published in 2011. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to IEC TS 62433 1:2011:

Incorporation of a data exchange format for an integrated circuit's model representation.

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The text of this International Standard is based on the following documents:

CDV	Report on voting
47A/1042/CDV	47A/1055/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 62433 series, under the general title *EMC IC modelling*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

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